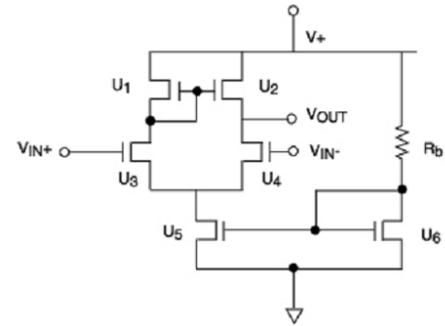


MOSFET DIFFERENTIAL AMPLIFIER (TWO-WEEK LAB)

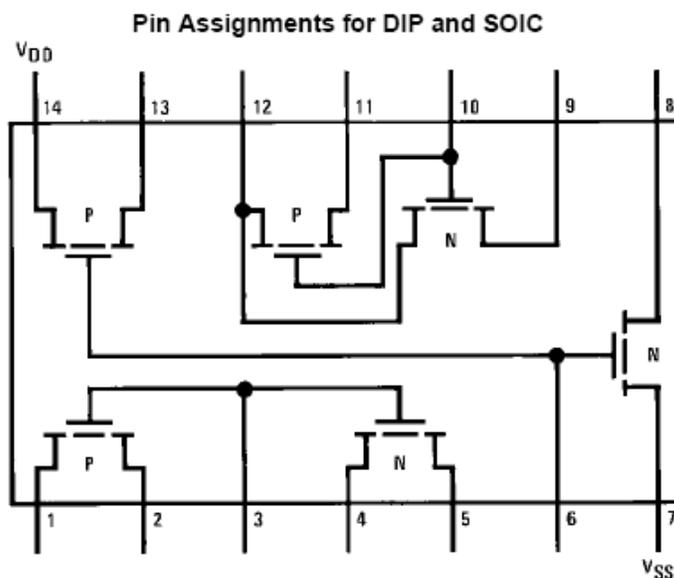
BACKGROUND

The MOSFET is by far the most widely used transistor in both digital and analog circuits, and it is the backbone of modern electronics. One of the most common uses of the MOSFET in analog circuits is the construction of differential amplifiers. The latter are used as input stages in op-amps, video amplifiers, high-speed comparators, and many other analog-based circuits. MOSFET differential amplifiers are used in integrated circuits, such as operational amplifiers, they provide a high input impedance for the input terminals. A properly designed differential amplifier with its current-mirror biasing stages is made from matched-pair devices to minimize imbalances from one side of the differential amplifier to the other.



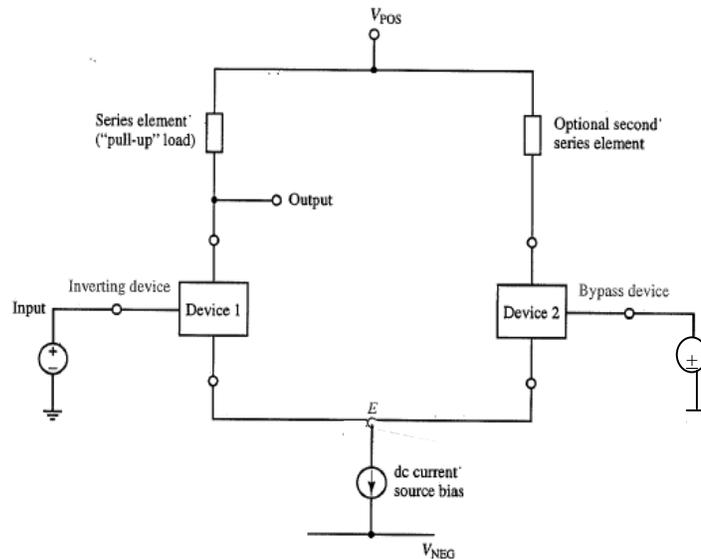
In this lab, you will design a differential amplifier by first verifying its operation in PSPICE, then building and testing your circuit stage by stage.

In your lab kit, you will find one or more CD4007 integrated circuits. (The letter prefix may vary; it's the number 4007 that matters.) This IC contains a number of NMOS and PMOS devices, as shown below. You may assume that all the NMOS transistors are matched to each other (same value of K and threshold voltage V_{TR}), and that all the PMOS devices are similarly matched to each other. Use the devices in this integrated circuit when building your differential amplifier, as requested in Levels 2 and 3.



BACKGROUND

The general topology of a differential amplifier is shown below. Two active devices are connected to a positive voltage supply via passive series elements. The transistors must be a matched pair (i.e., two matched MOSFETs or two matched BJTs). The "pull up" loads are similarly matched to each other. The lower terminals of the active devices are connected together, and a dc current source pulls current down toward the negative voltage bus to effect the bias. The controlling input ports of the devices are connected to input signals.



If the input signals are designated v_1 and v_2 , they can be decomposed into two linear combinations, one called the differential mode, and the other the common mode. The differential mode is defined by the following equation:

$$v_{idm} = v_1 - v_2$$

Similarly, the common mode, equal to the average value of the signals, is defined by:

$$v_{icm} = \frac{v_1 + v_2}{2}$$

These definitions allow the actual input signals v_1 and v_2 to be expressed as linear combinations of their differential and common modes:

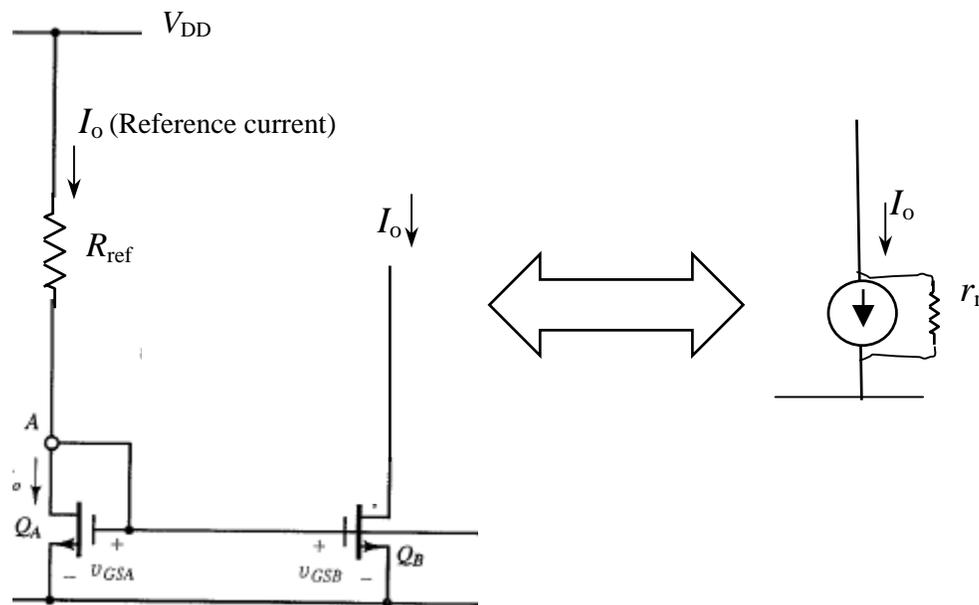
$$v_1 = v_{icm} + \frac{v_{idm}}{2} = \frac{v_1 + v_2}{2} + \frac{v_1 - v_2}{2} \equiv v_1$$

$$v_2 = v_{icm} - \frac{v_{idm}}{2} = \frac{v_1 + v_2}{2} - \frac{v_1 - v_2}{2} \equiv v_2$$

because the small-signal model of the amplifier is linear, its total response will be equal to the superposition of its responses to, respectively, the differential and common modes of the input signals.

Current Mirror.

The common-mode gain of the differential amplifier will be small (desirable) if the small-signal Norton, resistance r_n of the biasing current source is large. As we have discussed in class, the biasing current source is not a naturally occurring element, but must be synthesized from other transistors. In most situations, the designer will choose some form of *current mirror* to produce the equivalent current source. The circuit on the left, shown below, is equivalent in all respects to the symbolic current-source component on the right.



In the current mirror circuit shown on the left, the reference current is set by the resistor. The voltage across the latter is given by the voltage drop across R_{ref} . Because the two MOSFETs are matched, and have precisely the same gate-source and threshold voltages ($V_{GSA} = V_{GSB}$), their drain currents will be equal. Thus, the current I_o becomes a replica, or "mirror image" of the reference current. As long as Q_B remains in its constant current region, then this replication will take place. Note that Q_A automatically operates in its constant current region, because its gate is connected to its drain.

The Norton resistance r_n the current source will be equal to the output resistance r_o of Q_B , as determined by the upward slope of that transistor's voltage-current characteristic. The latter is associated with the Early voltage, as discussed in class and in the text.

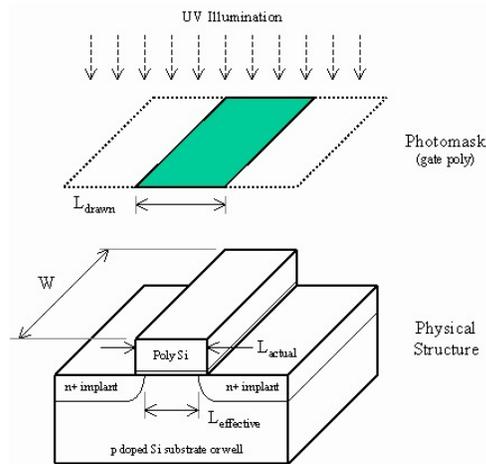
MOSFET Conductance Parameter.

If one studies the semiconductor physics that makes a MOSFET work, one can determine that the following formula gives the value of conductance parameter K :

$$K = (\mu_e \epsilon_{ox} / 2t_{ox})(W/L)$$

The constant μ_e is the electron mobility of the semiconductor, and ϵ_{ox} is the dielectric constant of the oxide layer under the MOSFET gate. The parameter t_{ox} is the physical thickness of the gate oxide layer.

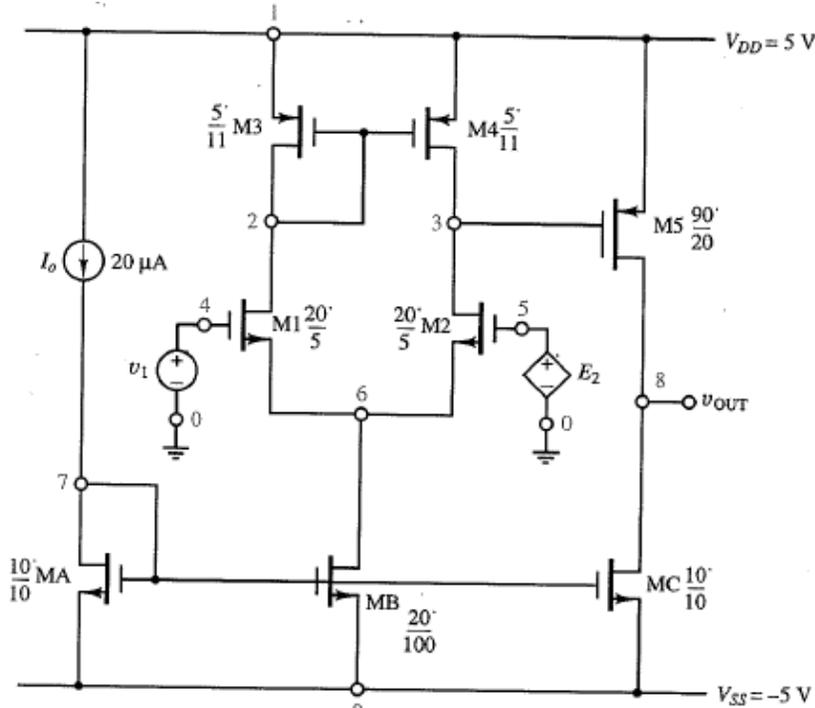
Two key parameters are the width W and length L of the MOSFET as it is laid out on the integrated circuit. L is the distance between the drain and source terminals, and W is the lateral width of the entire device, as shown below:



Level 1:

Consider the circuit shown below, for which the following parameters may be assumed: $|V_{TR}| = 1\text{ V}$, $K_N = 2 \times 10^{-5}\text{ A/V}^2$, $K_P = 10^{-5}\text{ A/V}^2$ and $V_A = 100\text{ V}$ (that is, the channel-width parameter $\lambda = 0.01\text{ V}^{-1}$). Here, the conductance parameters K_N and K_P are the values that a device of dimension $1\text{ }\mu\text{m} \times 1\text{ }\mu\text{m}$ device would have (i.e., $W = L = 1\text{ }\mu\text{m}$).

The fractional number next to each MOSFET symbol shows its W/L ratio (length and width values given in microns).



$V_{TRN} = |V_{TRP}| = 1\text{ V}$, $\mu_e C_{ox} = 20\text{ }\mu\text{A/V}^2$, $\mu_h C_{ox} = 10\text{ }\mu\text{A/V}^2$, and $V_{AN} = V_{AP} = 100\text{ V}$.

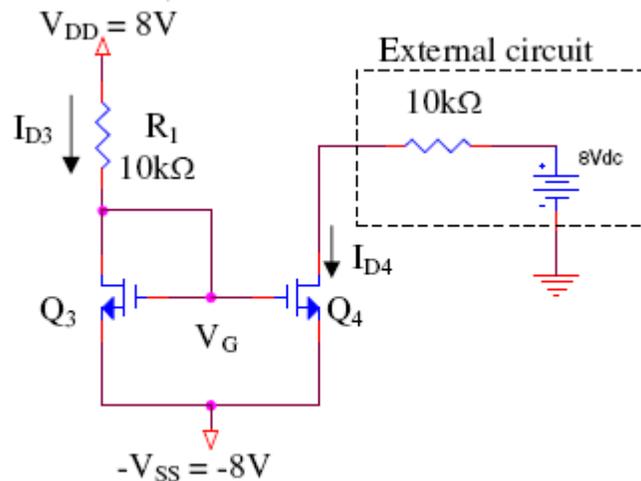
a) Use PSPICE to find the bias values of all the numbered node voltages. Record them in your notebook, then compare them with the values computed by hand, and provided in the Appendix.

b) Use PSPICE to plot the output voltage at nodes 2, 3, and v_{out} in response to a differential-mode input. Specifically, sweep v_1 from -1mV to $+1\text{mV}$, and make E_2 equal to $-v_1$.

Level 2

Build the current mirror circuit shown to the right. Use two of the NMOS devices on your 4007 chip. Your current mirror will pull current out of an external circuit comprised of a $10\text{-k}\Omega$ resistor and an 8-V dc source.

Measure I_{D3} with either an ammeter, or by measuring the voltage drop across R_1 and applying Ohm's law. Confirm that I_{D4} is the mirror image of I_{D3} ; that is $I_{D4} = I_{D3}$.

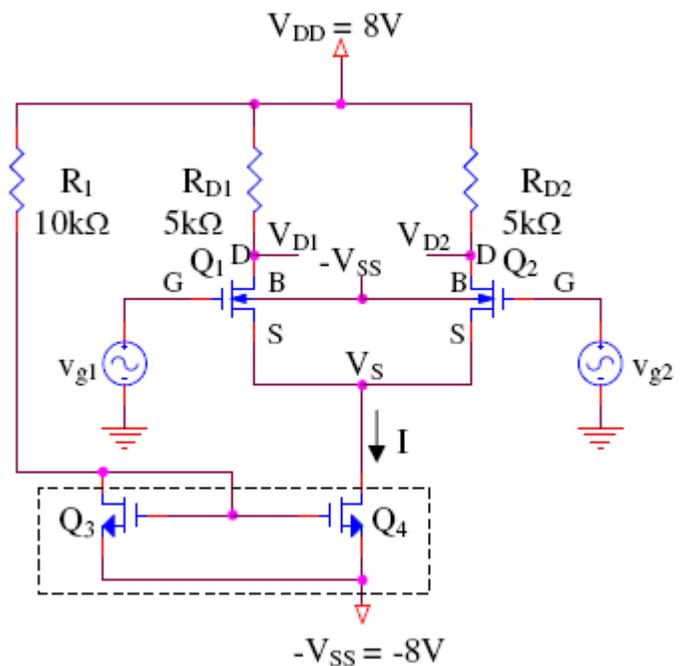


Level 3

Using the current mirror from Level 2, use additional transistors to build the differential amplifier shown to the right.

a) Confirm that the bias values V_{D1} and V_{D2} to lie approximately midway between the two supply voltages V_{DD} and V_{SS} .

b) Measure and record the differential-mode and common-mode gains of your amplifier.



APPENDIX

- Find the bias currents through each leg of the current mirror

Given that $I_A = I_o = 20 \mu\text{A}$, the various bias currents become, via Eqs. (12.67) and (12.68),

$$I_B = \frac{W_B/L_B}{W_A/L_A} I_o = \frac{20/100}{10/10} 20 \mu\text{A} = 4 \mu\text{A} \quad (12.76)$$

and

$$I_C = \frac{W_C/L_C}{W_A/L_A} I_o = \frac{10/10}{10/10} 20 \mu\text{A} = 20 \mu\text{A} \quad (12.77)$$

- Find the bias value of node voltage V_C

This node voltage will be equal to $V_{DD} - V_{SG3}$. Computing the gate-to-source voltage $V_{SG3} \equiv -V_{GS3}$ requires knowledge of $|K_3|$. From the given data,

$$|K_3| = \frac{1}{2} \frac{W_3}{L_3} \mu_h C_{ox} = \frac{5}{2(11)} (10 \mu\text{A}/\text{V}^2) = 2.27 \mu\text{A}/\text{V}^2 \quad (12.78)$$

Using this value of $|K_3|$, and the value $I_3 = I_B/2 = 2 \mu\text{A}$, it follows that

$$\begin{aligned} V_{SG3} &= (I_3/|K_3|)^{1/2} + |V_{TRP}| \\ &= [(2 \mu\text{A})/(2.27 \mu\text{A}/\text{V}^2)]^{1/2} + 1 \text{ V} \approx 1.9 \text{ V} \end{aligned} \quad (12.79)$$

and $V_C = V_{DD} - V_{SG3} = 5 \text{ V} - 1.9 \text{ V} = 3.1 \text{ V}$.

- Find the bias value of node voltage V_B

For the W/L values indicated in Table 1, the K parameters of Q_1 and Q_2 become

$$K_1 = K_2 = \frac{1}{2} \frac{W_1}{L_1} \mu_e C_{ox} = \frac{20}{2(5)} (20 \mu\text{A}/\text{V}^2) = 40 \mu\text{A}/\text{V}^2 \quad (12.80)$$

With $I_1 = I_2 = I_B/2 = 2 \mu\text{A}$, and with v_1 and v_2 held at dc ground by input signal sources, it follows that

$$\begin{aligned} V_{GS1} = V_{GS2} &= (I_1/K_1)^{1/2} + V_{TRN} \\ &= [(2 \mu\text{A})/(40 \mu\text{A}/\text{V}^2)]^{1/2} + 1 \text{ V} \approx 1.2 \text{ V} \end{aligned} \quad (12.81)$$

where $V_B = 0 - V_{GS1} = -1.2 \text{ V}$.

- Find the bias value of node voltage V_{D2}

The value of this node voltage is determined by V_{SG5} , which is, in turn, determined by the current

$$I_5 = I_C = \frac{W_C/L_C}{W_A/L_A} I_o = \frac{10/10}{10/10} (20 \mu\text{A}) = 20 \mu\text{A} \quad (12.82)$$

and the conductance parameter

$$|K_5| = \frac{1}{2} \frac{W_5}{L_5} \mu_h C_{ox} = \frac{90}{2(20)} (10 \mu\text{A}/\text{V}^2) = 22.5 \mu\text{A}/\text{V}^2 \quad (12.83)$$

Specifically, from the $v-i$ equation of Q_5 , it follows that

$$\begin{aligned} V_{SG5} &= (I_5/|K_5|)^{1/2} + |V_{TRP}| \\ &= [(20 \mu\text{A})/(22.5 \mu\text{A}/\text{V}^2)]^{1/2} + 1 \text{ V} \approx 1.9 \text{ V} \end{aligned} \quad (12.84)$$

Note that this voltage is identical to V_{SG3} , as computed in Eq. (12.79), because the W/L ratios of Q_B , Q_C , Q_3 , and Q_5 satisfy Eq. (12.72). Finally, from KVL,

$$V_{D2} = V_{DD} - V_{SG5} = 5 \text{ V} - 1.9 \text{ V} = 3.1 \text{ V} \quad (12.85)$$

which is identical to the previously computed voltage of node C .

Small Signal Differential-Mode Performance

The CMOS amplifier of Fig. 12.15 will respond to both differential- and common-mode signals. Its gain under differential-mode excitation can be easily derived using the results of Section 8.4.3. In this case, the incremental output resistance r_{o4} of Q_4 acts as the pull-up load to Q_2 . As noted in Eq. (8.187), the differential-mode gain observed at the drain of Q_2 , as enhanced by the current-mirror action of Q_3 and Q_4 , becomes

$$A_{\text{dm-se2}} = \frac{v_{d2}}{v_{\text{idm}}} = g_{m2}(r_{o2} \parallel r_{o4}) \quad (12.86)$$

where $v_{\text{idm}} = v_1 - v_2$. Because r_{o4} is comparable to r_{o2} , both resistances are included in the equation.

The signal v_{d2} from the drain of Q_2 is fed to the gate of Q_5 . This latter transistor acts as a p -channel inverter actively loaded by r_{oC} of Q_C . The gain of the second stage thus becomes

$$\frac{v_{\text{out}}}{v_{d2}} = -g_{m5}(r_{oC} \parallel r_{o5}) \quad (12.87)$$

Note that r_{o5} is included in this equation because it is comparable to r_{oC} .

The loading of the v_{d2} node by the gate of Q_5 is negligible, because the latter presents a pure capacitive load to the former. The overall signal gain of the two-stage cascade thus can be determined by simply multiplying together the individual gain equations (12.86) and (12.87), yielding

$$A_{\text{dm}} = \frac{v_{\text{out}}}{v_{\text{idm}}} = -g_{m2}g_{m5}(r_{o2} \parallel r_{o4})(r_{oC} \parallel r_{o5}) \quad (12.88)$$

We note that $g_m = 2\sqrt{KI_D}$ for a MOSFET in the constant-current region, and that $r_o = V_A/I_D$, where V_A is the MOSFET's Early voltage. Given that $I_2 = I_4$ and $I_5 = I_C$, Eq. (12.88) can be expressed in the alternative form

$$\begin{aligned} A_{\text{dm}} &= -(2\sqrt{K_2 I_2})(2\sqrt{K_5 I_5}) \frac{V_{A2}}{I_2} \left\| \frac{V_{A4}}{I_4} \times \frac{V_{AC}}{I_C} \right\| \frac{V_{A5}}{I_5} \\ &= -4\sqrt{K_2 K_5} \sqrt{I_2 I_5} \frac{(V_{AN}/I_2)(V_{AP}/I_2)}{V_{AN}/I_2 + V_{AP}/I_2} \frac{(V_{AN}/I_5)(V_{AP}/I_5)}{V_{AN}/I_5 + V_{AP}/I_5} \\ &= -4\sqrt{K_2 K_5} \sqrt{I_2 I_5} \frac{1}{I_2} \frac{1}{I_5} \left(\frac{V_{AN} V_{AP}}{V_{AN} + V_{AP}} \right)^2 \\ &= -4 \left(\frac{K_2 K_5}{I_2 I_5} \right)^{1/2} \left(\frac{V_{AN} V_{AP}}{V_{AN} + V_{AP}} \right)^2 \end{aligned} \quad (12.89)$$

where V_{AN} and V_{AP} are the Early voltages of the n -channel and p -channel devices, respectively. If $V_{AN} = V_{AP} = V_A$, the last term in Eq. (12.89) becomes $(V_A^2/2V_A)^2 = V_A^2/4$, so that the equation reduces to

$$A_{\text{dm}} = -V_A^2 \left(\frac{K_2 K_5}{I_2 I_5} \right)^{1/2} \quad (12.90)$$

Note that A_{dm} becomes larger as I_2 and I_5 are reduced. This effect occurs because the incremental output resistances r_{o2} , r_{o4} , r_{oC} , and r_{o5} of Q_2 , Q_4 , Q_C , and Q_5 become larger with decreasing magnitude of drain current I_D .

As these results show, the circuit designer has several degrees of freedom in setting the gain of a CMOS op-amp. Given knowledge of the process-dependent parameters V_{TR} , V_A , and $\mu\epsilon_{\text{ox}}/t_{\text{ox}} = \mu C_{\text{ox}}$ for n -channel and p -channel devices, where $K = \mu C_{\text{ox}} W/(2L)$, the open-loop gain of the amplifier can be set by appropriately choosing the W/L ratios of each device.